

MS/RF PCM/PROCESS CHECKLIST WORKING GROUP MEETING MINUTES

Date: May 20, 2010
Location: Teleconference
Time: 10:00am (Pacific)
Participants:

Chelsea Boone – GSA
David Schwan – RF Micro Devices (RFMD)
Steffen Richter – X-FAB
Ehrenfried Seebacher – austriamicrosystems AG
Paul Hurwitz – Jazz Semiconductor
Kulwant Egan – Intersil
Tim Turner – Texas Semicon Labs
Philippe Jansen – IMEC

Meeting Purpose:

To make a decision on a measurement definition for each parameter description in the parameter list spreadsheet. We will not cover all parameter descriptions in one meeting. This will be an on-going process.

End Result/Conclusions:

- Per the working group's feedback, definitions were selected for various parameter descriptions. To view the definitions selected, please see Version 5 of the PCM parameter list at http://www.gsaglobal.org/ams/index_wg.aspx?tab=2 (under Resources).
- Next Meeting: We will again continue to revise Version 5 and select the appropriate measurement definitions for parameter descriptions. **June 24, 2010, 10:00am (Pacific)**